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Joint ICTP-IAEA Advanced Workshop on High Sensitivity 2D & 3D Characterisation and Imaging with Ion Beams | (smr 2856)

Wednesday 28 September 2016

DAY 3 - LB (Euler Lecture Hall) (08:30-13:00)

time	title	presenter
08:30	Pitfalls in IBA data analysis (I)	BARRADAS, Nuno P.
09:30	Pitfalls in IBA data analysis (II) - Calculation of uncertainty budget	BARRADAS, Nuno P.
10:30	Coffee break	
11:00	Secondary Ion Mass Spectroscopy - SIMS, Cluster-SIMS and MeV-SIMS	WEBB, Roger
12:00	Lunch break	

DAY 3: VISIT TO SYNCHROTRON ELETTRA - (13:00-18:00)

time	title	presenter
13:00	Bus transfer to Synchrotron Elettra	
14:00	Welcome and overview of Synchrotron-based analytical techniques and Elettra	GREGORATTI, Luca
15:00	Laboratory visit	GREGORATTI, Luca
16:00	The SYRMEP X-ray imaging beamline at Elettra: recent achievements and future perspectives	TROMBA, Giuliana
16:30	Presentation of the TwinMic beamline	GIANONCELLI, Alessandra
17:30	Departure from Elettra Sincrotrone and return to the ICTP	